

# Search Notes



Application/Control No.

10/020,177

Examiner

DANG T. TON

Applicant(s)/Patent under Reexamination

ONO ET AL.

Art Unit

2616

## SEARCHED

Class	Subclass	Date	Examiner
<i>updated</i>		<i>3/26/06</i>	<i>F.D</i>

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
<i>370</i>	<i>535</i>	<i>3/26/06</i>	<i>F.D</i>

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
<i>Interference searched</i>	<i>3/26/06</i>	<i>F.D</i>